

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10584634	IKEDA ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Sophie Hon	1783	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
428	1.3,1.32-1.33	6/22/10	SH
349	137	"	"

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST text search attached	6/22/10	SH
Reviewed STIC EIC Search by searcher Huang, Mei Q. dated 9/26/08	"	"
Reviewed correlated appln 11/886,258	"	"

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>